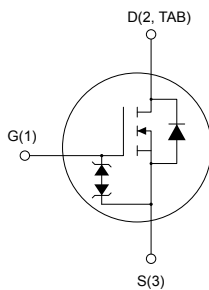
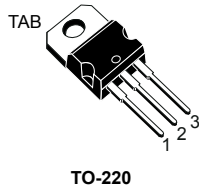


# N-channel 600 V, 94 mΩ typ., 28 A MDmesh DM2 Power MOSFET in a TO-220 package



## Features

| Order code  | $V_{DS}$ | $R_{DS(on)}$ max. | $I_D$ |
|-------------|----------|-------------------|-------|
| STP35N60DM2 | 600 V    | 110 mΩ            | 28 A  |

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

## Applications

- Switching applications

## Description

This high-voltage N-channel Power MOSFET is part of the MDmesh DM2 fast-recovery diode series. It offers very low recovery charge ( $Q_{rr}$ ) and time ( $t_{rr}$ ) combined with low  $R_{DS(on)}$ , rendering it suitable for the most demanding high-efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

### Product status link

[STP35N60DM2](#)

### Product summary

|            |             |
|------------|-------------|
| Order code | STP35N60DM2 |
| Marking    | 35N60DM2    |
| Package    | TO-220      |
| Packing    | Tube        |

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

| Symbol         | Parameter                                                       | Value      | Unit             |
|----------------|-----------------------------------------------------------------|------------|------------------|
| $V_{DS}$       | Drain-source voltage                                            | 600        | V                |
| $V_{GS}$       | Gate-source voltage                                             | $\pm 25$   | V                |
| $I_D$          | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$  | 28         | A                |
|                | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 17         |                  |
| $I_{DM}^{(1)}$ | Drain current (pulsed)                                          | 112        | A                |
| $P_{TOT}$      | Total power dissipation at $T_C = 25\text{ }^\circ\text{C}$     | 210        | W                |
| $dv/dt^{(2)}$  | Peak diode recovery voltage slope                               | 50         | V/ns             |
| $dv/dt^{(3)}$  | MOSFET $dv/dt$ ruggedness                                       | 50         | V/ns             |
| $T_{stg}$      | Storage temperature range                                       | -55 to 150 | $^\circ\text{C}$ |
| $T_J$          | Operating junction temperature range                            |            | $^\circ\text{C}$ |

1. Pulse width is limited by safe operating area.
2.  $I_{SD} \leq 28\text{ A}$ ,  $di/dt \leq 900\text{ A}/\mu\text{s}$ ,  $V_{DS}(\text{peak}) < V_{(BR)DSS}$ ,  $V_{DD} = 400\text{ V}$ .
3.  $V_{DS} \leq 480\text{ V}$ .

**Table 2. Thermal data**

| Symbol     | Parameter                               | Value | Unit                      |
|------------|-----------------------------------------|-------|---------------------------|
| $R_{thJC}$ | Thermal resistance, junction-to-case    | 0.6   | $^\circ\text{C}/\text{W}$ |
| $R_{thJA}$ | Thermal resistance, junction-to-ambient | 62.5  | $^\circ\text{C}/\text{W}$ |

**Table 3. Avalanche characteristics**

| Symbol   | Parameter                                                                                                            | Value | Unit |
|----------|----------------------------------------------------------------------------------------------------------------------|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not-repetitive (pulse width limited by $T_J$ max.)                                  | 6     | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_J = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 650   | mJ   |

## 2 Electrical characteristics

( $T_C = 25\text{ }^{\circ}\text{C}$  unless otherwise specified)

**Table 4. On/off states**

| Symbol        | Parameter                         | Test conditions                                                                             | Min. | Typ. | Max.    | Unit          |
|---------------|-----------------------------------|---------------------------------------------------------------------------------------------|------|------|---------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage    | $V_{GS} = 0\text{ V}$ , $I_D = 1\text{ mA}$                                                 | 600  |      |         | V             |
| $I_{DSS}$     | Zero gate voltage drain current   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 600\text{ V}$                                             |      |      | 10      | $\mu\text{A}$ |
|               |                                   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 600\text{ V}$ , $T_C = 125\text{ }^{\circ}\text{C}^{(1)}$ |      |      | 100     |               |
| $I_{GSS}$     | Gate-body leakage current         | $V_{DS} = 0\text{ V}$ , $V_{GS} = \pm 25\text{ V}$                                          |      |      | $\pm 5$ | $\mu\text{A}$ |
| $V_{GS(th)}$  | Gate threshold voltage            | $V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$                                          | 3    | 4    | 5       | V             |
| $R_{DS(on)}$  | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$ , $I_D = 14\text{ A}$                                                |      | 94   | 110     | m $\Omega$    |

1. Specified by design, not tested in production.

**Table 5. Dynamic**

| Symbol                     | Parameter                     | Test conditions                                                                                                                                  | Min. | Typ. | Max. | Unit     |
|----------------------------|-------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|----------|
| $C_{iss}$                  | Input capacitance             | $V_{DS} = 100\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0\text{ V}$                                                                             | -    | 2400 | -    | pF       |
| $C_{oss}$                  | Output capacitance            |                                                                                                                                                  | -    | 110  | -    | pF       |
| $C_{rss}$                  | Reverse transfer capacitance  |                                                                                                                                                  | -    | 2.8  | -    | pF       |
| $C_{oss\text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{GS} = 0\text{ V}$ , $V_{DS} = 0\text{ to }480\text{ V}$                                                                                      | -    | 190  | -    | pF       |
| $R_g$                      | Intrinsic gate resistance     | $f = 1\text{ MHz}$ , $I_D = 0\text{ A}$                                                                                                          | -    | 4.3  | -    | $\Omega$ |
| $Q_g$                      | Total gate charge             | $V_{DD} = 480\text{ V}$ , $I_D = 28\text{ A}$ , $V_{GS} = 0\text{ to }10\text{ V}$<br>(see the Figure 14. Test circuit for gate charge behavior) | -    | 54   | -    | nC       |
| $Q_{gs}$                   | Gate-source charge            |                                                                                                                                                  | -    | 14.6 | -    | nC       |
| $Q_{gd}$                   | Gate-drain charge             |                                                                                                                                                  | -    | 24.2 | -    | nC       |

1.  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

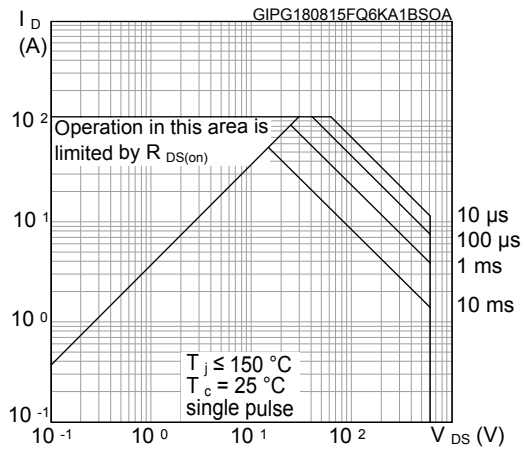
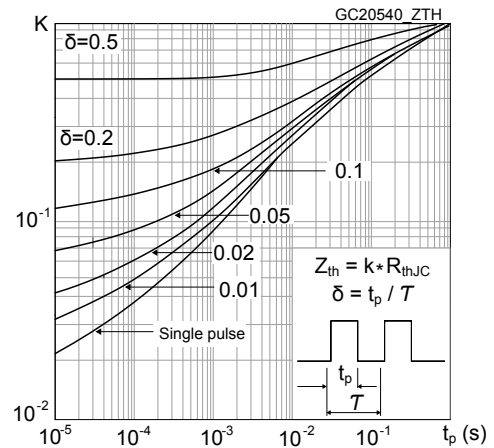
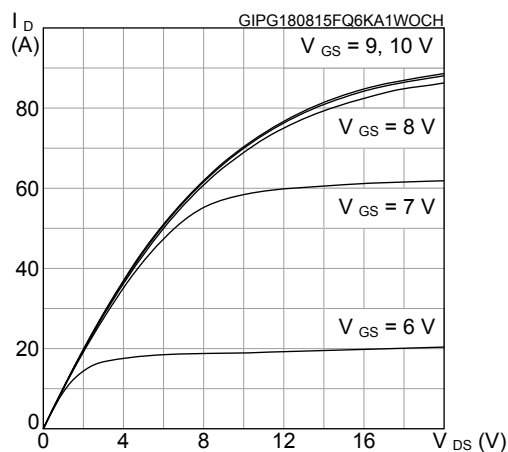
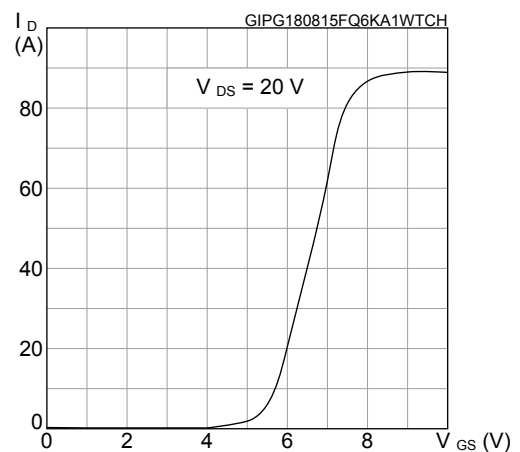
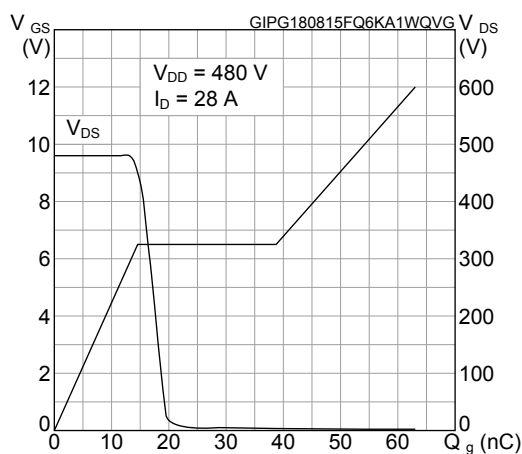
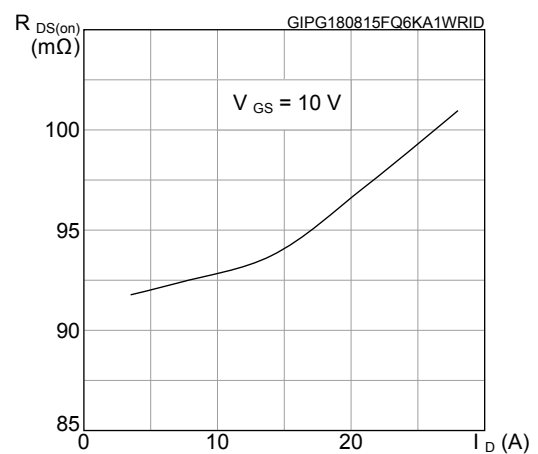
| Symbol       | Parameter           | Test conditions                                                                                             | Min. | Typ. | Max. | Unit |
|--------------|---------------------|-------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 300\text{ V}$ , $I_D = 14\text{ A}$ ,<br>$R_G = 4.7\text{ }\Omega$ , $V_{GS} = 10\text{ V}$       | -    | 21.2 | -    | ns   |
| $t_r$        | Rise time           |                                                                                                             | -    | 17   | -    | ns   |
| $t_{d(off)}$ | Turn-off delay time | (see the Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform) | -    | 68   | -    | ns   |
| $t_f$        | Fall time           |                                                                                                             | -    | 10.7 | -    | ns   |

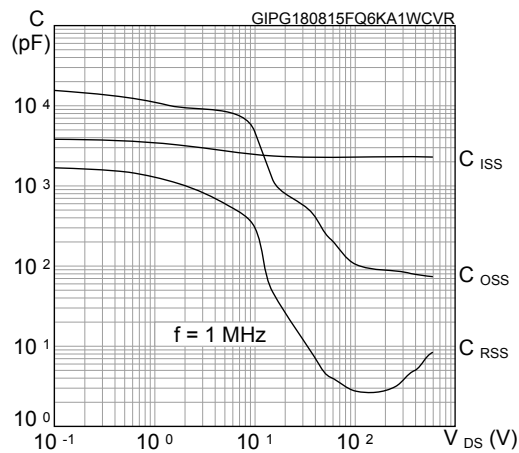
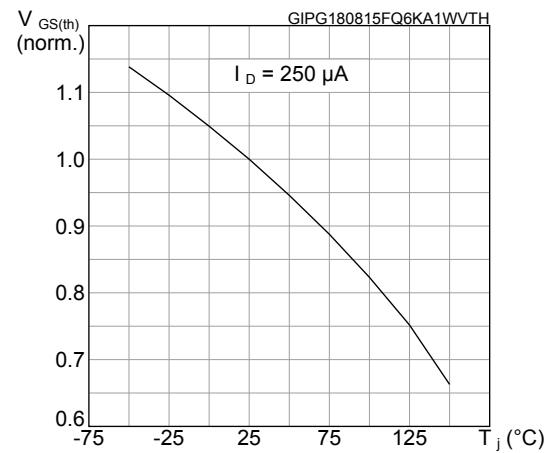
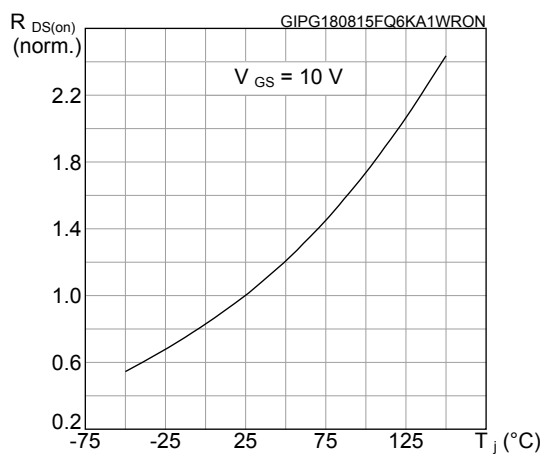
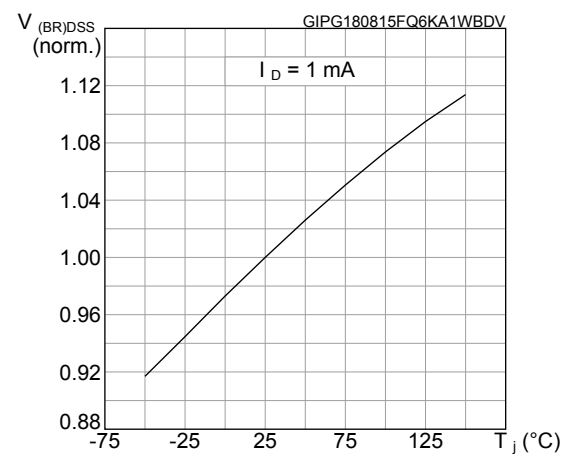
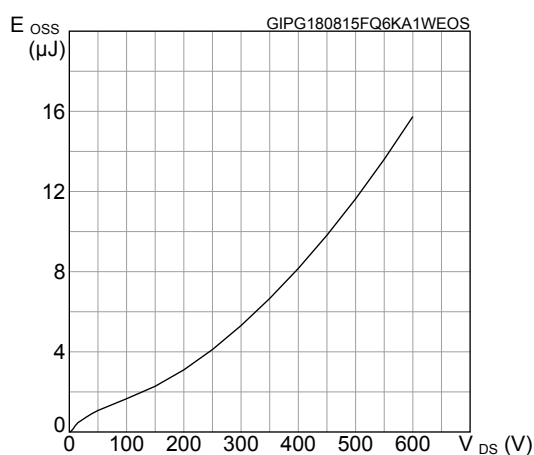
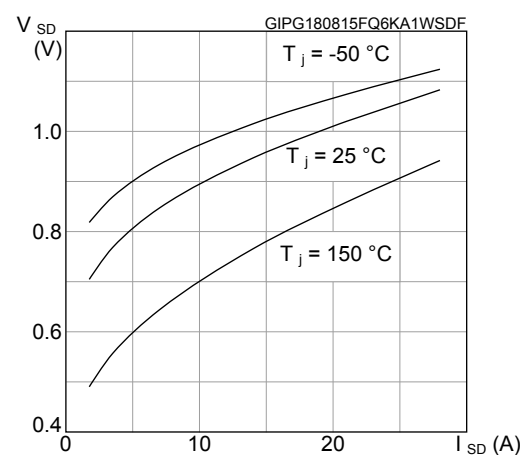
**Table 7. Source-drain diode**

| Symbol          | Parameter                     | Test conditions                                                                                                             | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|-----------------------------------------------------------------------------------------------------------------------------|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                             | -    |      | 28   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                             | -    |      | 112  | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $I_{SD} = 28\text{ A}$ , $V_{GS} = 0\text{ V}$                                                                              | -    |      | 1.6  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 28\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 60\text{ V}$                                     | -    | 120  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                             | -    | 0.57 |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see the Figure 15. Test circuit for inductive load switching and diode recovery times)                                     | -    | 10.2 |      | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 28\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 60\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$ | -    | 215  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                             | -    | 1.89 |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see the Figure 15. Test circuit for inductive load switching and diode recovery times)                                     | -    | 17.7 |      | A             |

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

**Figure 1. Safe operating area**

**Figure 2. Normalized transient thermal impedance**

**Figure 3. Typical output characteristics**

**Figure 4. Typical transfer characteristics**

**Figure 5. Typical gate charge characteristics**

**Figure 6. Typical drain-source on-resistance**


**Figure 7. Typical capacitance characteristics**

**Figure 8. Normalized gate threshold vs temperature**

**Figure 9. Normalized on-resistance vs temperature**

**Figure 10. Normalized breakdown voltage vs temperature**

**Figure 11. Typical output capacitance stored energy**

**Figure 12. Typical reverse diode forward characteristics**


### 3 Test circuits

**Figure 13. Test circuit for resistive load switching times**


AM01468v1

**Figure 14. Test circuit for gate charge behavior**


AM01469v1

**Figure 15. Test circuit for inductive load switching and diode recovery times**

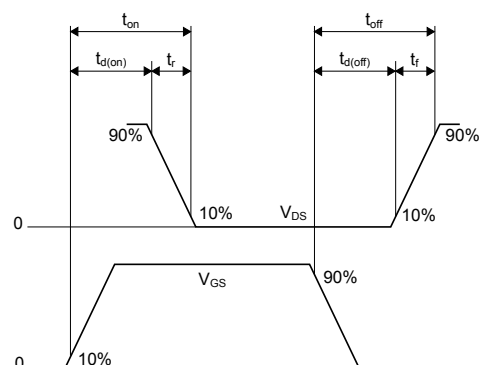

AM01470v1

**Figure 16. Unclamped inductive load test circuit**


AM01471v1

**Figure 17. Unclamped inductive waveform**


AM01472v1

**Figure 18. Switching time waveform**


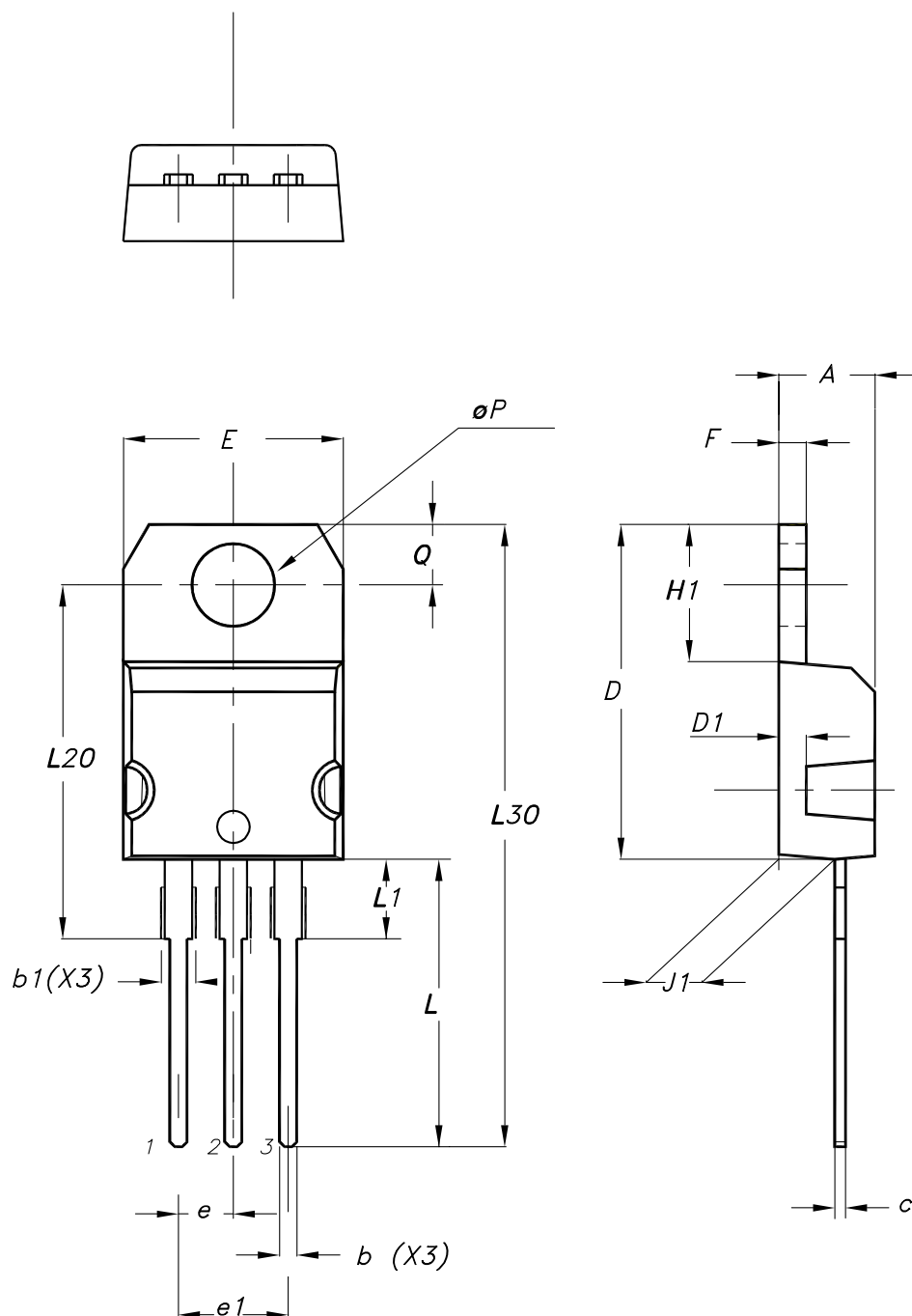
AM01473v1

## 4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 TO-220 type A package information

Figure 19. TO-220 type A package outline



0015988\_typeA\_Rev\_24

**Table 8. TO-220 type A package mechanical data**

| Dim.          | mm    |       |       |
|---------------|-------|-------|-------|
|               | Min.  | Typ.  | Max.  |
| A             | 4.40  |       | 4.60  |
| b             | 0.61  |       | 0.88  |
| b1            | 1.14  |       | 1.55  |
| c             | 0.48  |       | 0.70  |
| D             | 15.25 |       | 15.75 |
| D1            |       | 1.27  |       |
| E             | 10.00 |       | 10.40 |
| e             | 2.40  |       | 2.70  |
| e1            | 4.95  |       | 5.15  |
| F             | 1.23  |       | 1.32  |
| H1            | 6.20  |       | 6.60  |
| J1            | 2.40  |       | 2.72  |
| L             | 13.00 |       | 14.00 |
| L1            | 3.50  |       | 3.93  |
| L20           |       | 16.40 |       |
| L30           |       | 28.90 |       |
| øP            | 3.75  |       | 3.85  |
| Q             | 2.65  |       | 2.95  |
| Slug flatness |       | 0.03  | 0.10  |

## Revision history

**Table 9. Document revision history**

| Date        | Version | Changes                                                                                         |
|-------------|---------|-------------------------------------------------------------------------------------------------|
| 10-Sep-2015 | 1       | Initial version                                                                                 |
| 13-Feb-2026 | 2       | Updated <a href="#">Section 4.1</a> : TO-220 type A package information.<br>Minor text changes. |

## Contents

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